

# WEBINAR | P-HIL Simulation

for Power Systems and Power Electronics Applications

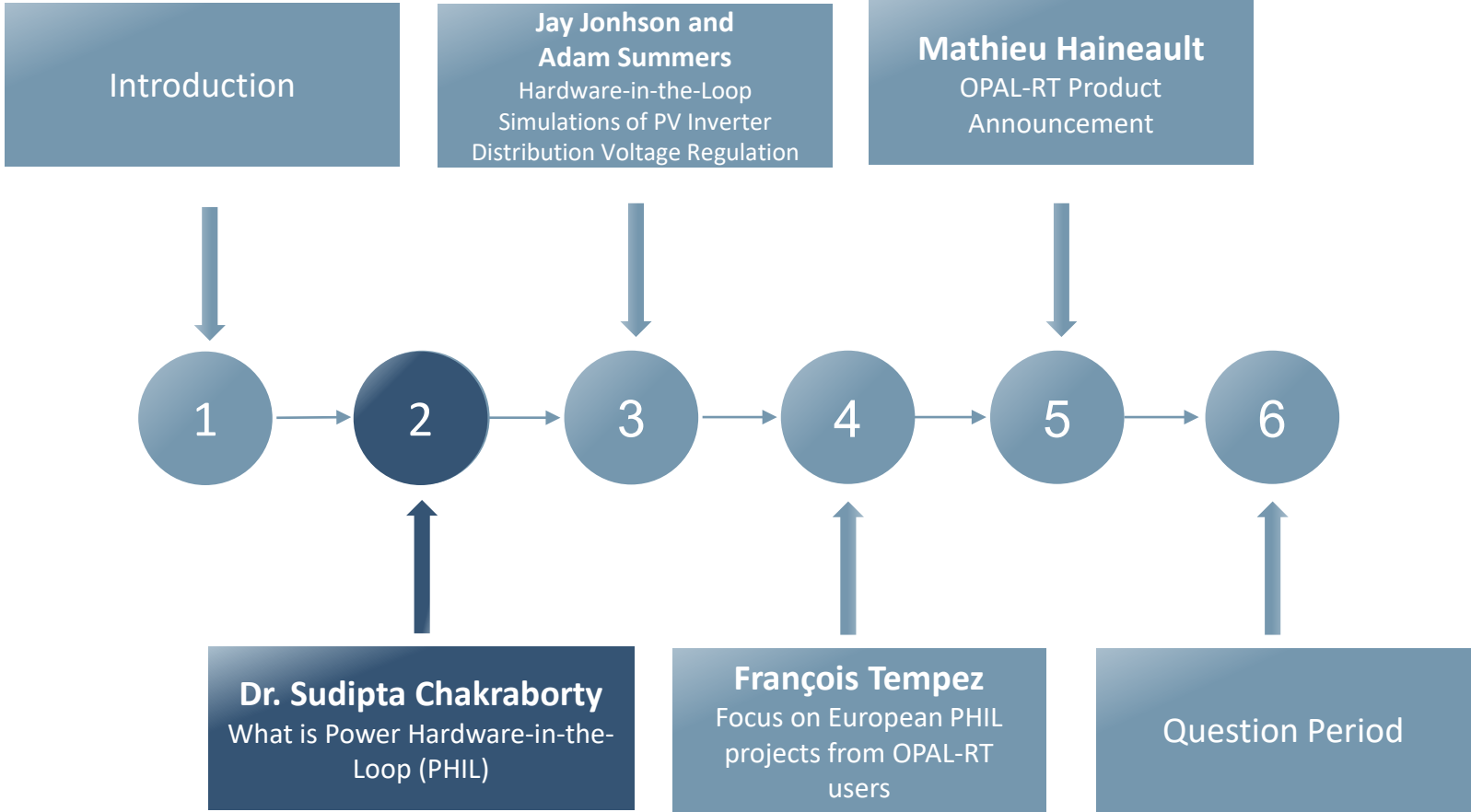


**OPAL-RT**  
TECHNOLOGIES

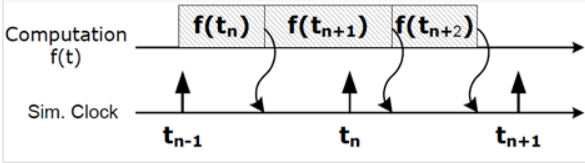
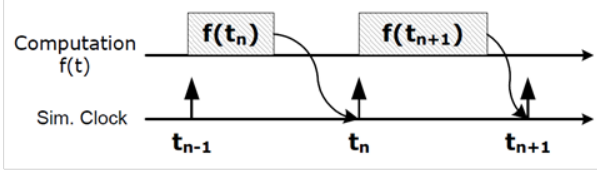
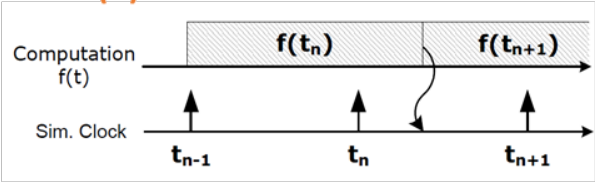


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# WEBINAR OUTLINE

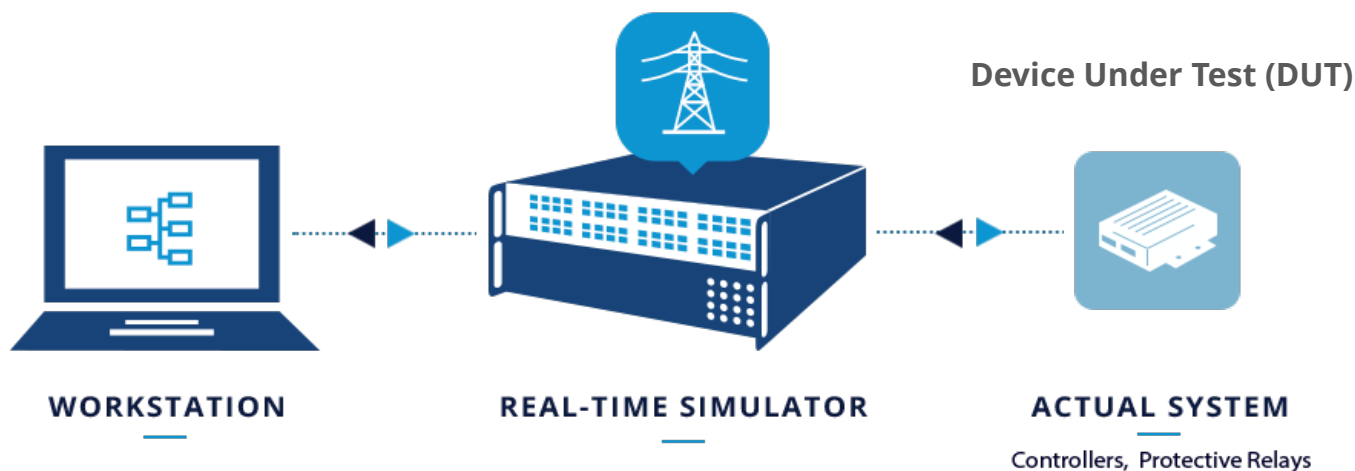


# REAL-TIME SIMULATION

<p><b>(A) Faster-than-Real-Time</b></p> 	<p><b>(B) Real-Time</b></p> 	<p><b>(C) Slower-than-Real-Time</b></p> 
<p>Can be achieved with <b>desktop/offline simulations</b> (simpler models only)</p>	<p>Strictly requires an <b>RTS</b>. Studies with or without HIL can be performed.</p>	<p>Usually the case of <b>desktop/offline simulations</b></p>
<p>Can be achieved with an <b>RTS</b> (<b>Accelerated</b> mode, where model allows for clock acceleration)</p>	<p>Hardware-in-the-Loop (<b>HIL</b>) is the general term for test applications of an <b>RTS</b></p>	<p>Best achieved with an <b>RTS</b> with complex models (<b>Accelerated</b> mode, where model is too complex for running in RT, but the RTS allows for faster simulation than desktop simulation)</p>
	<p>Controller HIL (<b>CHIL</b>)</p>	
	<p>Rapid Control Prototyping (<b>RCP</b>)</p>	
	<p>Power HIL (<b>PHIL</b>)</p>	
<p>← Software-in-the-Loop (<b>SIL</b>) →</p>		

# HARDWARE-IN-THE-LOOP (HIL)

- Hardware-in-the-loop (HIL) testing utilizes real-time simulation to connect and test actual hardware devices with simulation of the rest of the systems and test environments
- This allows users to perform realistic closed-loop tests without the need for testing on a real system
- While HIL typically refers to setups with low-voltage level signal connections, power hardware-in-the-loop (PHIL) can be employed for higher power testing

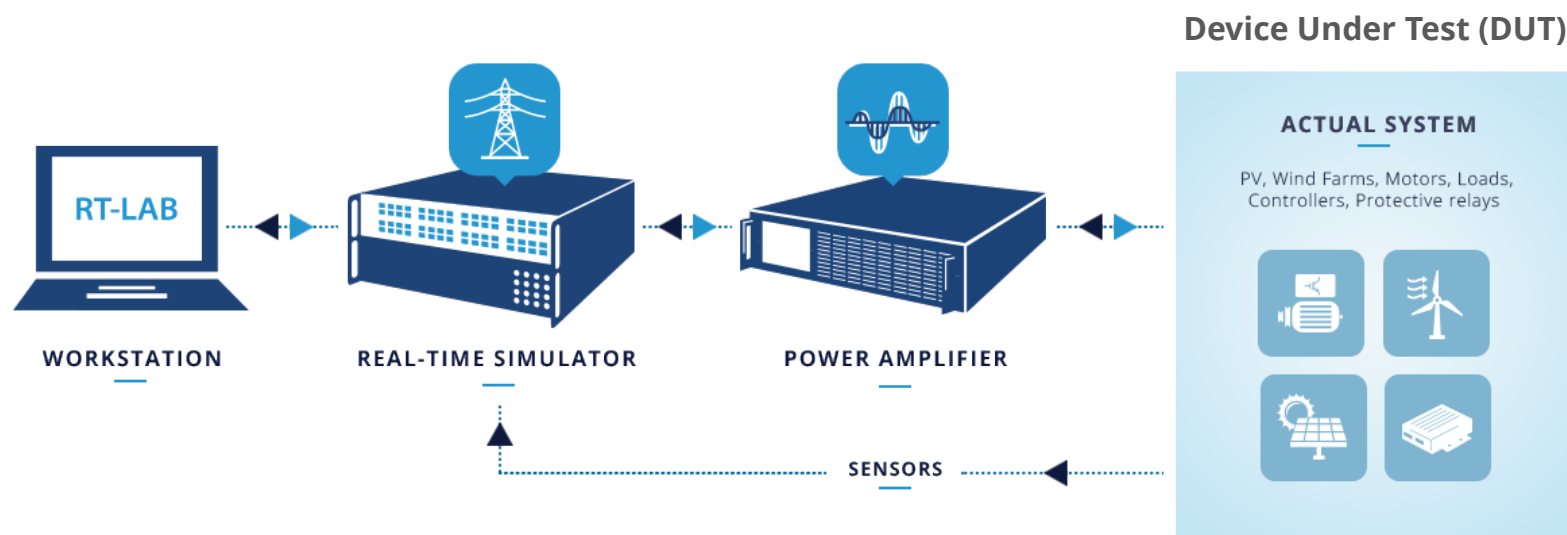


## DUT Examples

- Controllers
  - SCADA, EMS, DMS, Microgrid controllers
  - Power electronics controllers
  - Vehicle ECU
- Intelligent Electronic Devices
  - Protection devices
  - "Smart" sensors

# POWER HARDWARE-IN-THE-LOOP (PHIL)

- Power hardware-in-the-loop (PHIL) involves in creating a virtual power interface between the digital simulation and devices under test
- Typically, the power interface involves power amplifiers (voltage and/or current), which must be selected carefully depending on the application
- PHIL setup is more complex and typically much costlier due to cost of amplifier and sensing hardware



## DUT Examples

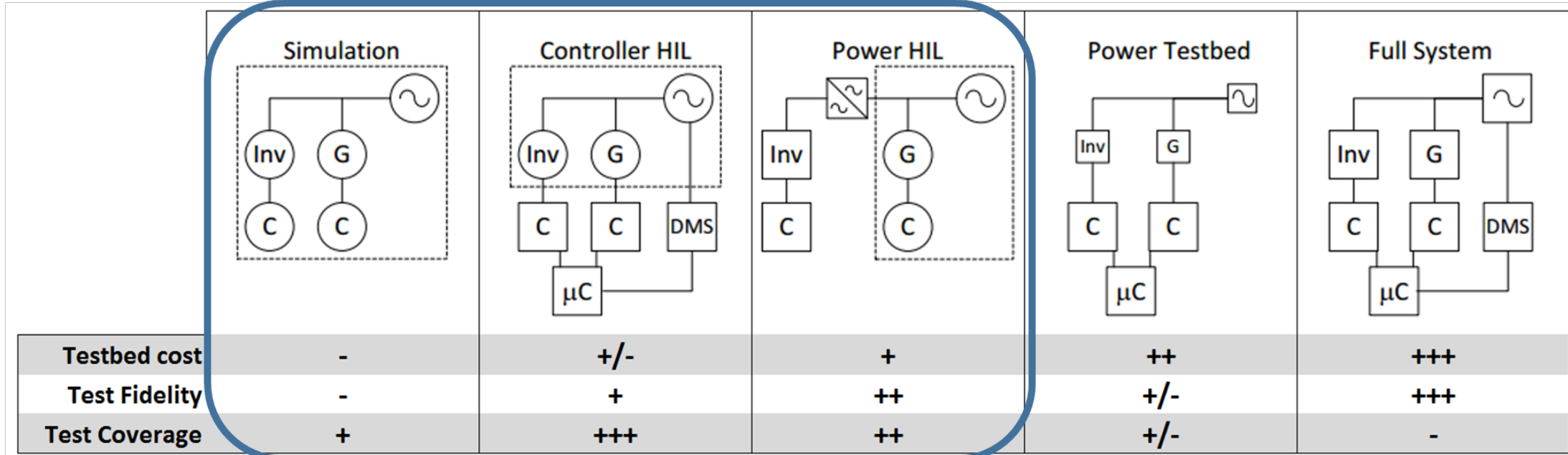
- Power converters (inverters, rectifiers, power supplies)
- Electric machines and drives
- Microgrid switch and PCC
- Batteries including BMS
- Electrical drivetrain for EV
- Vehicle charger

# TRADEOFFS BETWEEN TESTBEDS

## Applications of a Real-Time Simulator (RTS)



Figure modified from the concept originally proposed by MIT-LL [1]



- **Test fidelity** depends on purpose of testing, model validity and test setup. For Power Testbed, fidelity depends on equipment used and similarities between that and the real installation.
- **Test coverage** depends on purpose of testing and flexibility of running various ‘what-if’ scenarios. Pure simulation does not allow testing of real devices; but with good models, it is a powerful tool for design studies. CHIL provides the best coverage for testing control systems, such as microgrid controller, allowing fault scenarios, transitions and dispatch scenario functional testing.
- **PHIL** can provide good balance between test fidelity and test coverage at a cost that is lower than full-system testing.

[1] R.O. Salcedo, J.K. Nowocin, C.L. Smith, R.P. Rekha, E.G. Corbett, E.R. Limpaecher, J.M. LaPenta, TR-1203: Development of a Real-Time Hardware-in-the-Loop Power Systems Simulation Platform to Evaluate Commercial Microgrid Controllers, MIT Lincoln Laboratory, Lexington, MA, Feb. 2016.

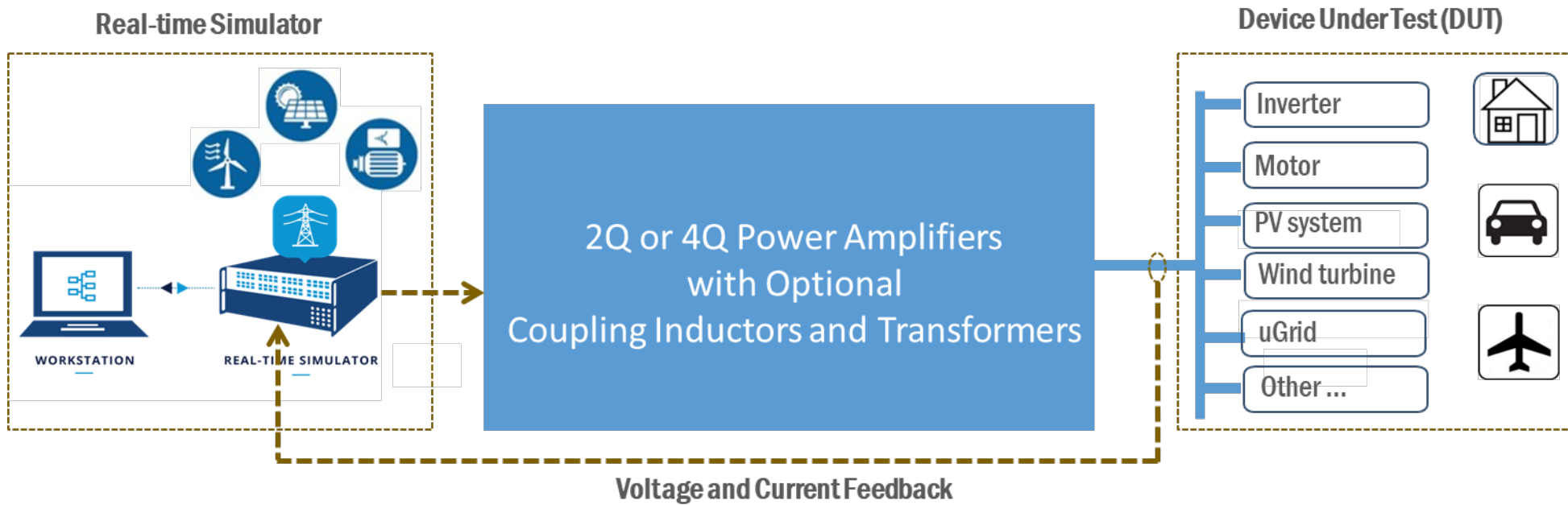


# BENEFITS OF PHIL

- PHIL allows developers to test a wider range of device characteristics than analog benches or dynos with less maintenance and setup time
  - Allowing robustness of the hardware under test over a wider variation of parameters, test conditions and faults
- In addition to interacting with the hardware, PHIL testing allows incorporation of real-world communication networks (Modbus, DNP3, 61850, etc.)
  - Allowing incorporation of real-world delays, latencies, cyber-events into the system-level validation
- PHIL creates a robust, flexible and reliable test platform
  - Allowing validation of complex, system-level, dynamic interactions between multiple devices, at-power, without costly field demonstration or detailed device models
  - Enabling tests that are not feasible or too risky to do with the real system (e.g. fault on feeder, over-speed on motors etc.)

# TYPICAL PHIL SETUP

- Amplifier
- Real-time simulator with inputs and outputs
- Sensors for feedback to simulator
- Real-time models along with interface algorithms, filtering, compensation, protection, etc.





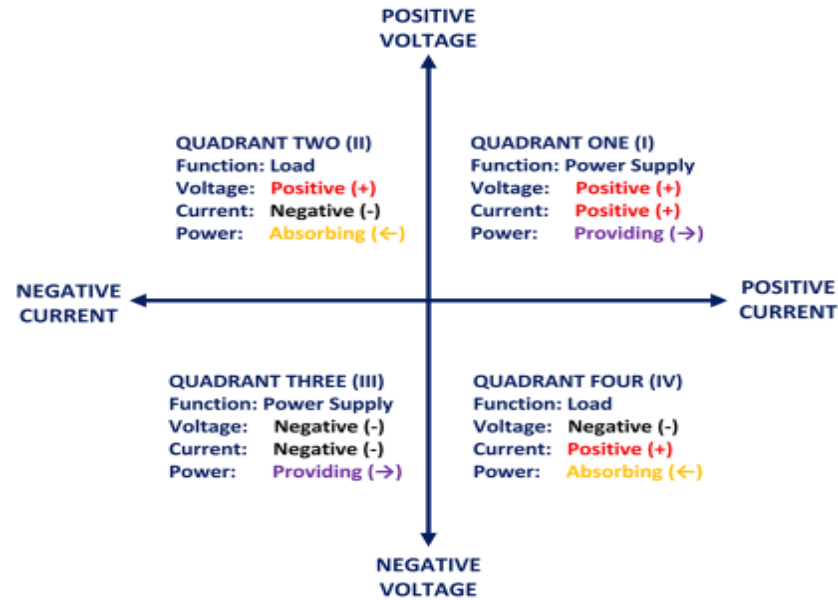
# AMPLIFIERS

- Amplifier selection is technical and is extremely sensitive to the application

## Sample Specifications

- Application : Motor / Grid / Inverter
- Power rating
- Number of phases
- Capabilities : AC / DC / AC-DC
- Type : 2Q / 4Q and Linear / Switching
- Nominal voltage, current and peak current
- Nominal frequency
- Frequency range
- Frequency resolution
- Output Impedance
- Harmonic distortion
- Amplifier slew rate
- Amplifier control type : Analog Out / SFP
- Feedback Measurement : Internal / External
- Parallel or series connection capabilities
- Amplifier size and weight
- Price range

## 2Q vs. 4Q Amplifiers



- 2Q amplifiers only generate power – requires additional sink (loads) for some applications
- 4Q amplifiers generates and absorbs power – more flexible and common now-a-days
- Not all amplifier can absorb 100% power

## Linear vs. Non-linear

Linear	Non-Linear
<ul style="list-style-type: none"> <li>• Voltage/Current amplifier</li> <li>• Higher bandwidth</li> <li>• Faster response</li> <li>• Lower flexibility</li> <li>• Bulky</li> <li>• Costly</li> </ul>	<ul style="list-style-type: none"> <li>• Switched mode</li> <li>• Lower bandwidth</li> <li>• Slower response</li> <li>• Higher flexibility</li> <li>• Smaller</li> <li>• Less costly</li> <li>• Higher power</li> </ul>

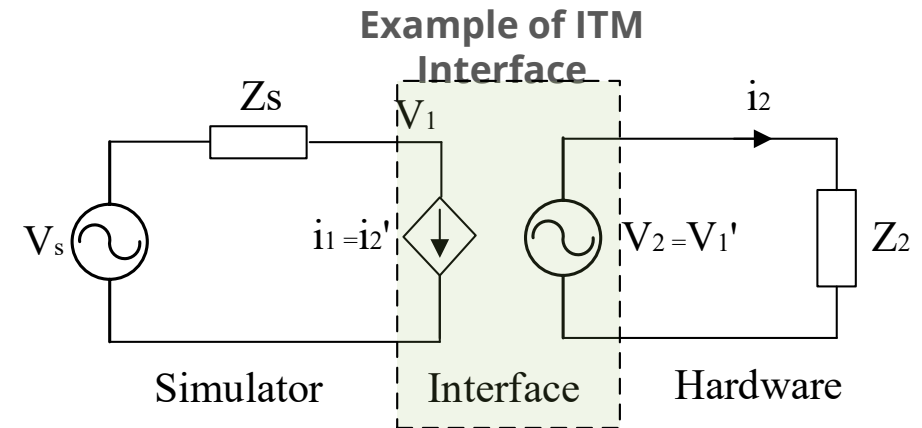
## Example of Amplifier



**And a newest one!!  
 You will hear about it  
 later**

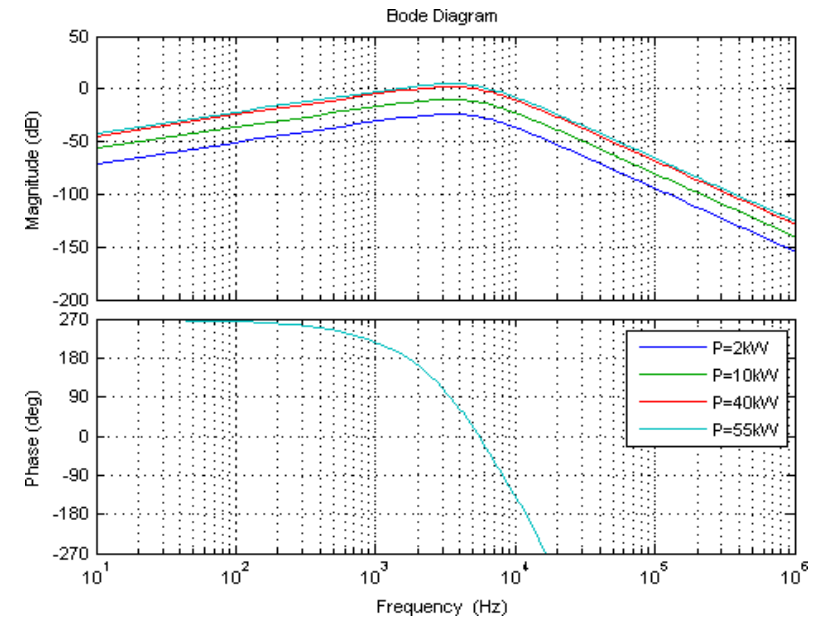
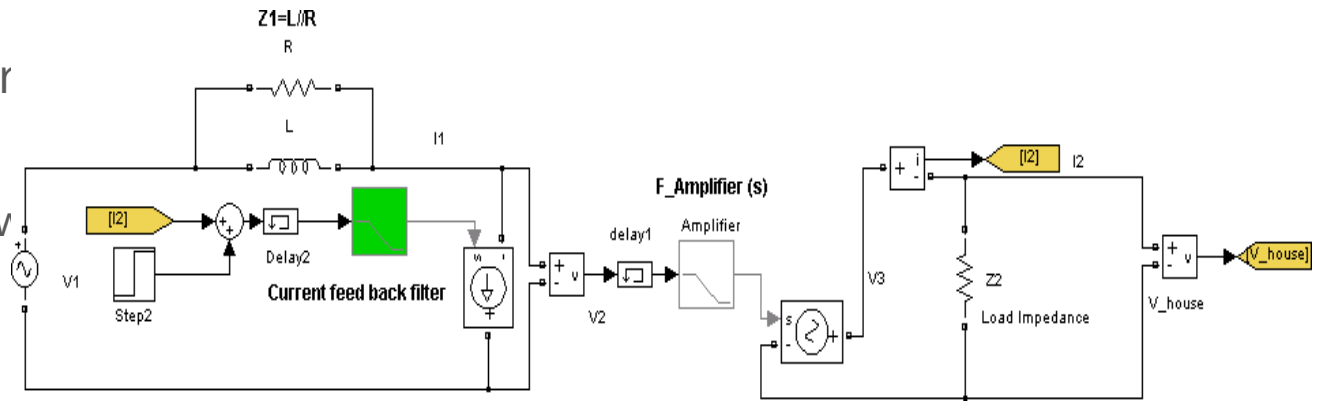
# OTHER CONSIDERATIONS FOR PHIL TESTING

- Interface algorithms
  - Ideal Transformer Model (ITM), Damping Impedance Method (DIM), Transmission Line Model (TLM), Partial Circuit Duplication (PCD), Time-variant First-order Approximation (TFA) [2]
- Filtering and compensation
  - Noise due to sensors, EMI/EMC can create issues in interfacing – introducing filters create unwanted delay and attenuation
  - Compensation algorithms often required to mitigate filtering effects
- Stability analysis
  - Closed loop PHIL system, including simulation, amplifier, sensors, can become unstable for certain operating conditions
  - Instability may damage equipment or result is loss of simulation fidelity



# PHIL STABILITY ANALYSIS

- Example shown here is based on ITM inter
- Stability depends on :
  - Ratio of load power to short-circuit pov
  - Type of load
  - Damping of source impedance
  - Power amplifier bandwidth
  - Simulator's sampling frequency
  - Use of current feedback filter
- Various methods for stabilization for ITM can be found in [3]



Determining the best interface and stabilization methods to ensure system stability and maximum accuracy must be done on a case-by-case basis

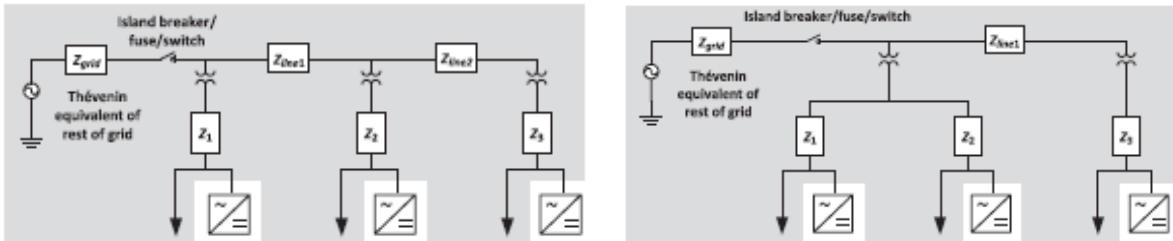
[3] A. Viehweider, G. Lauss, L. Felix, *Stabilization of Power Hardware-in-the-Loop simulations of electric energy systems*, Elsevier Simulation Modelling Practice and Theory, August 2011.



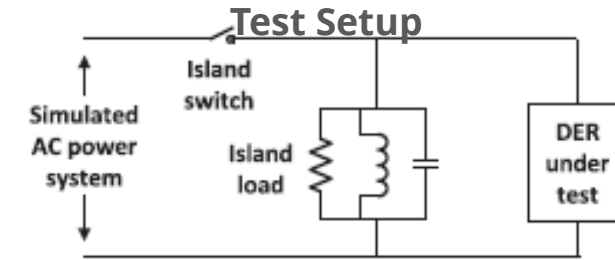
# PHIL EXAMPLE – INVERTER TESTING

- Multi-inverter islanding detection test platform [4]:
  - Efficient testing of a large number of island configurations simply by changing the distribution circuit model in the real-time simulator
  - Detailed models for the smart inverters are no longer required (“black box” approach)
  - Validation of islanding detection capability of the inverters with advanced grid support functions (VRR, FVRR etc.)

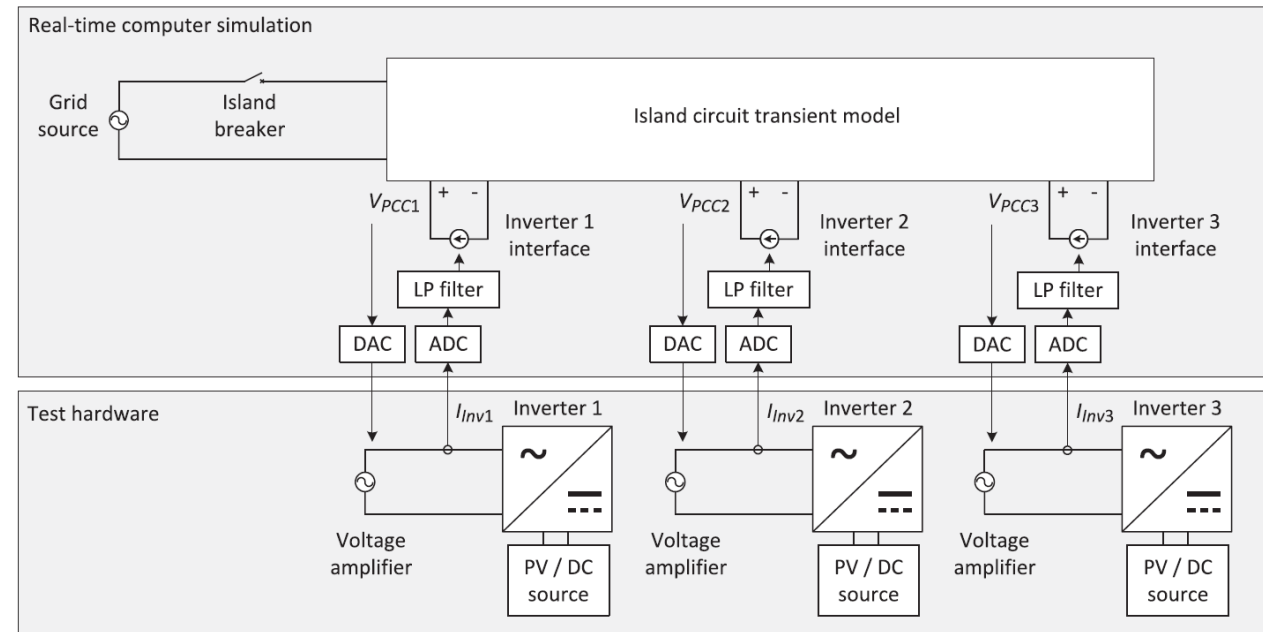
## Example Test Cases



## Conventional Islanding Detection



## PHIL Test Setup for Multi-inverter Islanding Detection Test



[4] A. F. Hoke, A. Nelson, S. Chakraborty, F. Bell, M. McCarty, *An Islanding Detection Test Platform for Multi-Inverter Islands Using Power HIL*, IEEE Transactions on Industrial Electronics, Oct. 2018.

# PHIL EXAMPLE – ADMS TESTBED

- Flexible testbed for Advanced Distribution Management System (ADMS):
  - Model large scale distribution systems for evaluating ADMS applications
  - Integration of real-time phasor-domain and electromagnetic transient simulations along with communication protocols
  - Integration of distribution system hardware and distributed energy resources for CHIL and PHIL experimentation
  - Multi-time scale, multi-platform test setup involving actual power and control hardware

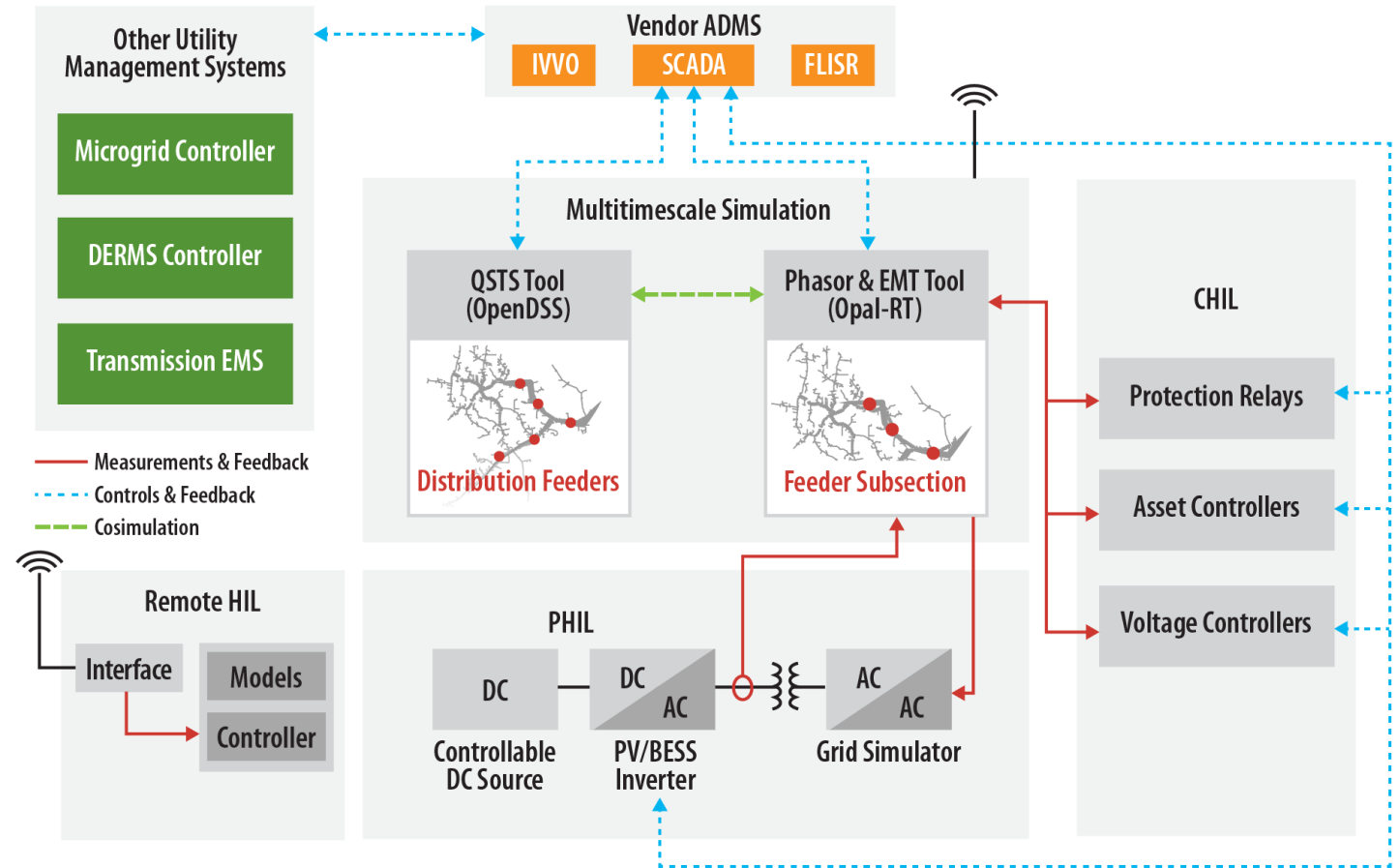
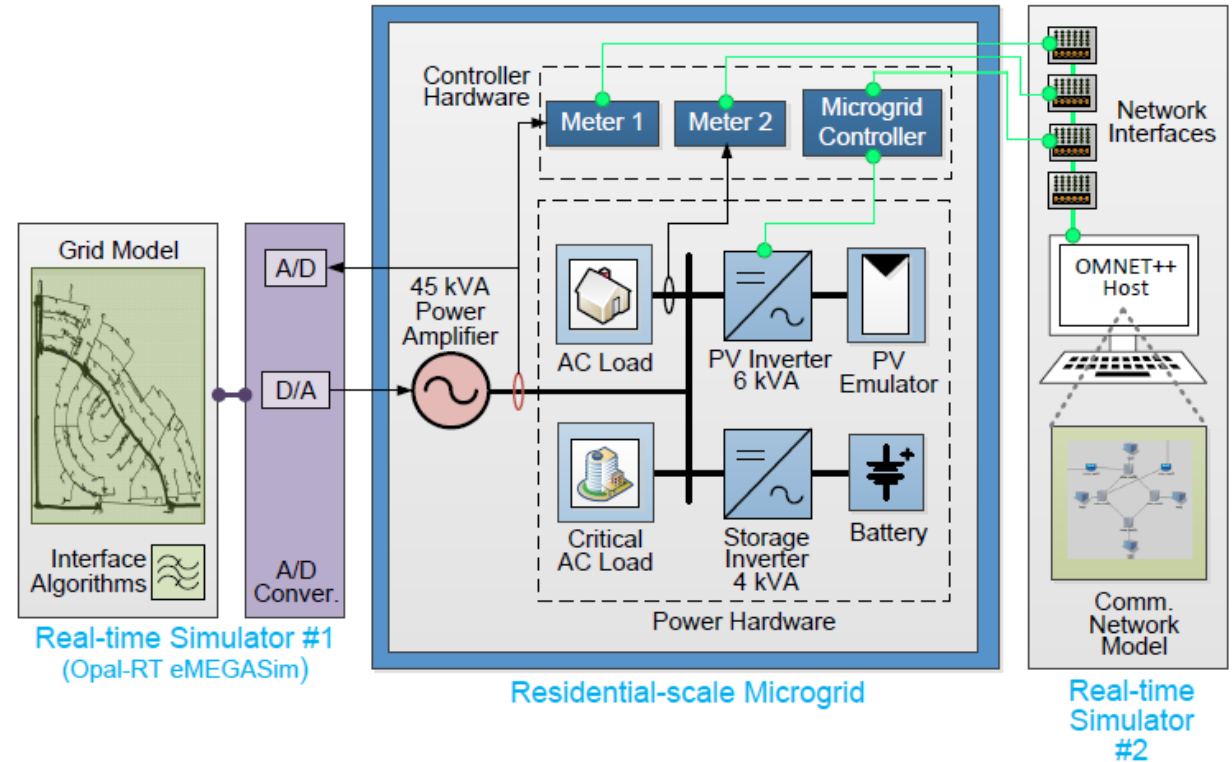


Figure source: NREL (from 2018 ISGT presentation)

# PHIL EXAMPLE – MICROGRID TESTBED

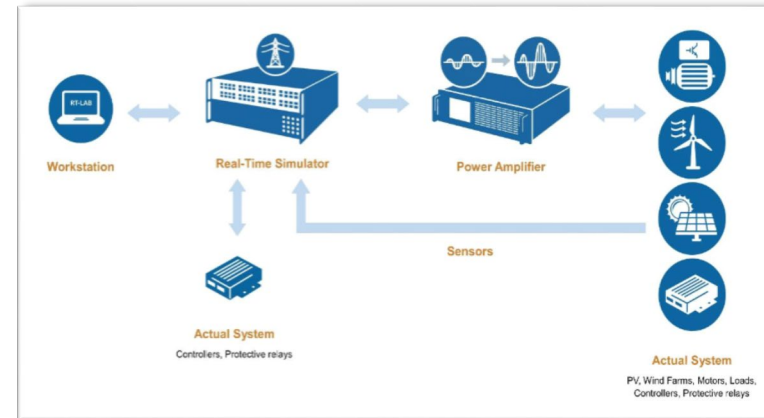
- Cyber-physical testbed for microgrid [5]:
  - Real-time models of an electrical distribution network in OPAL-RT platform
  - Real-time network-simulator-in-the-loop (NSIL) models in OMNET++
  - Physical power hardware, including a simplified microgrid controller, power meters, a smart PV inverter, and a battery storage inverter, interconnected using PHIL techniques
- Sample case studies demonstrated how communication delays could impact microgrid controller performance and the operation of the power grid



[5] B. Lundstrom, S. Chakraborty, G. Lauss, R. Bründlinger, R. Conklin, *Evaluation of system-integrated smart grid devices using software- and hardware-in-the-loop*, IEEE Power & Energy Society Innovative Smart Grid Technologies Conference (ISGT), 2016.

# THANK YOU!

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